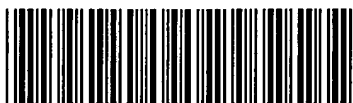


Search Notes

Application/Control No.

10/522,870

Examiner

Bin Shen

Applicant(s)/Patent under
Reexamination

OEHRVIK ET AL.

Art Unit

1657

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PubMed-see printout.	12/14/2006	BS